Electron Cloud Buildup Characterization

Using Shielded Pickup Measurements and

Custom Modeling Code

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L3 Electron cloud experimental region
PEP-II EC Hardware:
Chicane, upgraded SEY station (commissioning in May 2009)
Drift and Quadrupole diagnostic chambers

New electron cloud experimental regions in arcs
(after 6 wigglers moved to L0 straight)
Locations for collaborator experimental vacuum chambers

30 RFAs in drift regions, dipoles, quadrupoles, and wigglers

Custom vacuum chambers with shielded pickup detectors
Uncoated aluminum, and TiN, amorphous carbon, diamond-like carbon coatings
Shielded Pickup Design and Readout

8-bit digitizing oscilloscope

Bias +50 V

10 kΩ

0.1 µF

50 Ω

0.76 mm diameter

2 mm

Detail
The quantum efficiency for reflected photons and the secondary yield are both much smaller for conditioned TiN than for uncoated aluminum.

The carbon coating suppresses photoelectron production relative to the TiN coating, especially at high photoelectron energy. However, the secondary yield is somewhat higher.
**Electron cloud buildup modeling code**

**ECLOUD**

1. **Generation of photoelectrons**
   - A) Production energy, angle
   - B) Azimuthal distribution (v.c. reflectivity)

2. **Time-sliced cloud dynamics**
   - A) Cloud space charge force
   - B) Beam kick
   - C) Magnetic fields

3. **Secondary yield model**
   - A) True secondaries (yields > 1!)
   - B) Rediffused secondaries (high energy)
   - C) Elastic reflection (dominates at low energy)

4. **Shielded pickup model**
   - A) Acceptance vs incident angle, energy
   - B) Signal charge removed from cloud
   - C) Non-signal charge creates secondaries

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* Originated at CERN in the late 1990's
* Widespread application for PS, SPS, LHC, KEK, RHIC, ILC ...
  * Under active development at Cornell since 2008
* Successful modeling of CESRTA tune shift measurements
  * Interactive shielded pickup model implemented in 2010
  * Full POSINST SEY functions added as option 2010-2012
  * Flexible photoelectron energy distributions added 2011
* Synrad3D photon absorption distribution added 2011
Disentangling the Photoelectron Production Kinetic Energy Distribution from the Beam Kick Strengths

The early SPU signal from the leading bunch for a positron beam is largely due to photoelectrons produced on the bottom of the vacuum chamber. This is the closest production point where the beam kick attracts the photoelectrons toward the SPU. Thus the size and shape of the leading bunch signal is determined by the reflected photon rate, azimuthal distribution, the quantum efficiency for producing photoelectrons, and the kinetic energy distribution of the photoelectrons. In particular, the arrival time distribution determines the shape. By modeling the shape for different strengths of beam kick, we can determine the photoelectron energy distribution. An example of such an analysis is shown on the left. Note that the signal begins just a few nanoseconds after bunch passage even for weak beam kicks, indicating that high-energy photoelectrons were produced (hundreds of eV).
Two Power-Law Contributions

\[ F(E) = E^{P_1} \left( 1 + \frac{E}{E_0} \right)^{-P_2} \]

\[ E_0 = E_{\text{peak}} \left( P_2 - P_1 \right) / P_1 \]

This level of modeling accuracy was achieved with the photoelectron energy distribution shown below, using a sum of two power law distributions.

\[ E_{\text{peak}} = 80 \text{ eV} \quad P_1 = 4 \quad P_2 = 8.4 \]

The high-energy component (22%) has a peak energy of 80 eV and an asymptotic power of 4.4. Its contribution to the signal is shown as yellow circles in the lower left plot.

\[ E_{\text{peak}} = 4 \text{ eV} \quad P_1 = 4 \quad P_2 = 6 \]

The low-energy component (78%) has a peak energy of 4 eV and an asymptotic power of 2. Its contribution to the signal is shown as pink triangles.
Constraints on the kinetic energy distribution for secondary electrons

\[ f(E_{\text{sec}}) \sim E_{\text{sec}} \exp (-E_{\text{sec}} / E_{SEY}) \]

A Lower Bound on the \( E_{SEY} \) Parameter

The signal from a witness bunch following 14 ns after the leading bunch includes additionally a much larger contribution from secondary cloud electrons accelerated into the SPU detector by the witness-bunch kick.

The figures on the left show that if the secondary energy distribution does not include sufficiently high energies, the modeled 14-ns witness bunch signal shape is distorted and inconsistent with the measured signal.
Beam Conditioning in an Amorphous-carbon-coated Al Chamber

Shielded pickup signals measured in an amorphous-carbon-coated chamber in May (blue dotted line) and December (red dotted line) of 2010 for two bunches carrying $4.8 \times 10^{10}$ 5.3 GeV positrons 28 ns apart. The synchrotron radiation dose increased by a factor of twenty during this time interval. The ECLUSION model optimized for the May data is shown as blue circles, the error bars showing the model statistical uncertainties.

The leading bunch arises from photoelectrons produced on the bottom of the vacuum chamber. Careful tuning of the energy distribution and quantum efficiency for photoelectrons produced by reflected photons is required to reproduce its size and shape. The signal from the witness bunch includes additionally the contribution from secondary cloud electrons accelerated into the SPU detector by the witness bunch kick and is therefore crucially dependent on the secondary yield and production kinematics. Since the conditioning affects both signals similarly, we can conclude that the conditioning change is in the quantum efficiency rather than in the secondary yield.

The December measurement is reproduced by a 50% decrease in the modeled quantum efficiency for photoelectron production. A reduction in the secondary yield of 25% is inconsistent with the observed effect, since the leading bunch signal is unchanged.
Conditioning effect for a previously unprocessed a-C coating affects the quantum efficiency, not the SEY, as for the late conditioning process. The elastic yield value does not affect the 14-ns bunch.

The elastic yield value does influence the signal from the witness bunch delayed by 84 ns. An unprocessed elastic yield as high as 20% can be excluded.
Superposition of eleven two-bunch SPU signals with time delays between 12 and 100 ns, compared to the ECLOUD model result.

The cloud lifetime following passage of the final bunch is determined by the elastic secondary process, because it dominates at low incident electron energy, while the true and rediffused secondary processes both produce secondaries with reduced energy.

This was the original motivation for the shielded pickup development and was the analysis of first priority. These analyses have shown cloud lifetimes for the coated chambers (TiN, amorphous carbon, and diamond-like carbon) to be dramatically shorter than for the uncoated aluminum chamber.

This early study shows discrepancies with the measured signals which were later found to be due to an unrealistic model for photoelectron production. Despite these deficiencies in the model, the conclusion that an elastic yield value of 0.05 is too low for this uncoated aluminum chamber is clear.

\[ \delta_0 = 0.05 \]
Witness bunch studies with delays up to 100 ns show clear sensitivity to the secondary elastic yield parameter, giving a value of about 0.75 for bare aluminum and about 0.05 for the TiN coating. The discriminating power is independent of the photoelectron model.
New Time-Resolved RFA's in L3

TR-RFA Vacuum Chamber

SECTION A-A

RFA Collector with 9 channels

RFA Structure Detail

92 mm

Ø89 mm

Retarding Grids

RFA Collectors

RFA Signals

Ceramic Spacers
New Time-Resolved RFA's in PEP-II
Chicane: Dipole Field On/Off

Chicane dipole field off

Central collectors dominate.

Chicane dipole field 45 G

Central collectors show a depletion zone. This is known to arise from the peak of the SEY curve and provides information on $E_{\text{max}}$. 
Conclusions and Next Steps

Conclusions

Time-resolved measurements of cloud buildup using shielded pickup detectors can provide remarkable discriminating power between photoelectron and secondary electron production processes. They also provide information distinguishing the various processes contributing to secondary electron production.

In particular, such time-resolved information is very sensitive to the production kinematics for both photoelectrons and secondary electrons.

New information using this method is also coming from the CERN PS. See G.Rumolo, these proceedings. IPAC’12, WEPPR010, F.Caspers et al, “The impressive resemblance (between simulation and measurement) suggests that our electron cloud model correctly describes the phenomenon and the rationale for the data analysis is promising.”

Next Steps

This summer we will remove the custom amorphous carbon and diamond-like carbon-coated vacuum chambers and replace them with uncoated aluminum and TiN-coated chambers. This will allow us to test the method of studying conditioning for coatings where the SEY is known to change.

Two additional time-resolved RFA's will be installed in grooved chambers, both uncoated and TiN-coated.

Extensive data samples for electron beams and with solenoidal magnetic fields remain to be analyzed.
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* Flexible photoelectron energy distributions added

* Synrad3D p.e. azimuthal distributions implemented 2011